

CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

A2 Global Electronics + Solutions 11701 28th Street North St. Petersburg, FL 33716

Fulfills the requirements of

ISO/IEC 17025:2017

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.

The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 22 December 2025 Certificate Number: AT-3054





SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

A2 Global Electronics + Solutions

11701 28th Street North St. Petersburg, FL 33716 Tony Giannetti 800 767 2637

TESTING

Valid to: **December 22, 2025** Certificate Number: AT-3054

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to A2 Global Electronics + Solutions to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

Version 004 Issued: October 6, 2023

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	AS608 <mark>1, 4.2.6.4</mark> AS6171/2		Freedom Scientific HD MAG,Nikon, Vision, Amscope Microscopes.
Solvent Test for Remarking	AS6081 4.2.6.4.3 A AS6171/2		Mineral spirits, Isopropyl alcohol
Dimensional Verification	AS6081, 4.2.6.4.2.2 AS6171/2	Electrical,	Calipers Auto Contactless Measurements
XRF	AS6081, 4.2.6.4.5 AS6171/3	Components	Multiple X-ray Fluorescence Testing Equipment
X-ray	AS6081, 4.2.6.4.4 AS6171/5		Multiple Radiological Testing Equipment
Scanning Electron Microscopy (SEM) Examination / Inspection	AS6171/2 Method F AS6081 Sect 4.2.6.4.3 C		Scanning Electron Microscope
Acoustic Microscopy	AS6171/6 AS6081 Appendix C.6		Scanning Acoustic Microscope (SAM)





Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, 4.2.6.4.6 AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Nisene JetEtch Pro, Paragon Oven.
Solderability	ANSI/J-STD-002		Solderability tester RPS 202TL-2 Reflow oven Madell Tech AE-R330
Wetting Balance Solder	ANSI/J-STD-002 MIL-STD-883		Wetting Balance Tester
Plating Thickness	AS6171/3		Plating Thickness Tester
Solvent Test for Resurfacing	AS6081 4.2.6.4.3 B AS6171/2		Hot plate, Acetone, 1-Methyl 2-Pyrrolidinone, Dynasolve 750 (or equivalent).

Electrical

Specific Tests and/or Properties Measured	Specificat <mark>ion, Standard,</mark> Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test	AS6171/7 Table 2 AS6081, Sect. C.3		
DC Test and Key Parameters AC, Switching, Functional Over Temperature	AS6171/7 MIL-STD-883	Electrical, Electronic and Electromechanical (EEE)	ATE and various Electronic Lab Equipment
DC Test and Key Parameters AC, Switching, Functional Ambient Temperature	AS6171/7 MIL-STD-883	Components	

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-3054.

Jason Stine, Vice President





CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

A2 Global Electronics + Solutions (America II Asia Pte Ltd)

151 Lorong Chuan #06-05A, #06-06, #06-07 New Tech Park 556741 Republic of Singapore

Fulfills the requirements of

ISO/IEC 17025:2017

and the

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.

The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 22 December 2023 Certificate Number: AT-3054.01









SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

A2 Global Electronics + Solutions (America II Asia Pte Ltd)

151 Lorong Chuan #06-05A, #06-06, #06-07 New Tech Park 556741 Republic of Singapore Chris Gear 800 767 2637

TESTING

Valid to: December 22, 2023 Certificate Number: AT-3054.01

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to A2 Global Electronics + Solutions to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

Version 003 Issued: May 9, 2023

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	AS6081, 4.2.6.4 AS6171/2A	Electrical, Electronic and Electromechanical (EEE) Components	Atto Instruments Microscope Nikon Vision, Amscope, Dinolight
Solvent Test for Remarking	AS6081 4.2.6.4.3 A AS6171/2A	Electrical, Electronic and Electromechanical (EEE) Components	Mineral spirits, Isopropyl alcohol
Solvent Test for Resurfacing	AS6081 4.2.6.4.3 B AS6171/2A	Electrical, Electronic and Electromechanical (EEE) Components	Hot plate, Acetone, 1-Methyl 2-Pyrrolidinone, Dynasolve 750.
Dimensional Verification	AS6081, 4.2.6.4.2.2 AS6171/2A	Electronic and Electromechanical (EEE) Components	Keyence – LM-1100, Tresna, Mitutoyo, TWG Calipers
XRF	AS6081, 4.2.6.4.5 AS6171/3	Electrical, Electronic and Electromechanical (EEE) Components	Thermo Scientific NITON Analyzer-XL3t





Non-Destructive Testing

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
X-ray	AS6081, 4.2.6.4.4 AS6171/5	Electronic and Electromechanical (EEE) Components	Truview Fusion, Truview 180
Scanning Electron Microscopy (SEM) Examination / Inspection	AS6171/2 Method F AS6081 Sect 4.2.6.4.3 C	Electrical, Electronic and Electromechanical (EEE) Components	Scanning Electron Microscope

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, 4.2.6.4.6 AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Paragon Furnace
Solderability	ANSI/J-STD-002	Electrical, Electronic and Electromechanical (EEE) Components	Hakko FX-301B Solder Pot

Electrical

Specific Tests and/or	Specification, Standard,	Items, Materials or	Key Equipment or
Properties Measured	Method, or Test Technique	Product Tested	Technology
Electrical Test	AS6171/7 Table 2 AS6081, Sect. C.3	Electrical, Electronic and Electromechanical (EEE) Components	ATE and various Electronic Lab Equipment

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-3054.01.

Jason Stine, Vice President

Version 003 Issued: May 9, 2023





CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

A2 Global Electronics + Solutions (America II Europe B.V.)

Rijnlanderweg 766, Unit C 2132NM Hoofddorp, The Netherlands

Fulfills the requirements of

ISO/IEC 17025:2017

and the

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.

The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 22 December 2023 Certificate Number: AT-3054.02









SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

A2 Global Electronics + Solutions (America II Europe B.V.)

Rijnlanderweg 766, Unit C 2132NM Hoofddorp, The Netherlands Chris Gear 800 767 2637

TESTING

Valid to: December 22, 2023 Certificate Number: AT-3054.02

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **A2 Global Electronics** + **Solutions** to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

Version 002 Issued: May 16, 2023

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	AS6081, 4.2.6.4 AS6171/2		Nikon, Vision, Amscope Microscopes
Solvent Test for Remarking	AS6081 4.2.6.4.3 A AS6171/2	Flectrical	Mineral spirits, Isopropyl alcohol, Acetone
Dimensional Verification	AS6081, 4.2.6.4.2.2 AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Digital Calipers, Microscopes, Keyence LM1100
XRF	AS6081, 4.2.6.4.5 AS6171/3		Thermo Scientific, NITON Analyzer-XL3t
X-ray	AS6081, 4.2.6.4.4 AS6171/5		Creative Electron Truview Fusion R





Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, 4.2.6.4.6 AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	JetEtch Pro, Paragon Furnace , NI Sense, CLC Controllaser
Marking Permanency / Solvency	AS6081 4.2.6.4.3 B AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Hot Plate, Multiple Chemicals
Solderability	ANSI/J-STD-002	Electrical, Electronic and Electromechanical (EEE) Components	Hakko FX-301B Solder Pot

Electrical

Specific Tests and/or	Specification, Standard,	Items, Materials or	Key Equipment or
Properties Measured	Method, or Test Technique	Product Tested	Technology
Electrical Test	AS6171/7 Table 2 AS6081, Section C.3	Electrical, Electronic and Electromechanical (EEE) Components	ATE and Various Electronic Lab Equipment

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-3054.02.

Jason Stine, Vice President

Version 002 Issued: May 16, 2023

